## ELEC-313 Lab 2: Diode Characterization

September 20, 2013

Date Performed: September 18, 2013 Partners: Charles Pittman

Stephen Wilson

- 1 Objective
- 2 Schematics

Circuit Tested

**Test Configuration** 

- 3 Procedure
- 4 Results
- 4.1 Part A

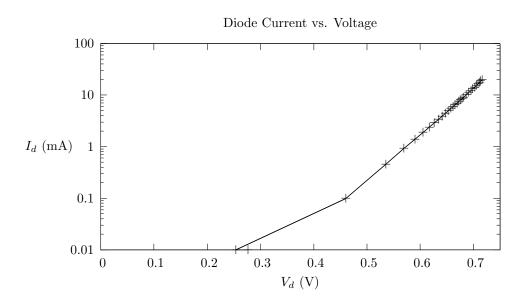


Figure 1: Diode characteristics measured in Part A.

- 4.2 Part B
- 5 Conclusion
- 6 Appendix

Equations

$R(\Omega)$	$V_d$ (V)	$I_d \text{ (mA)}$
200	0.751	46.00
500	0.713	18.60
1k	0.682	9.30
2k	0.650	4.70
5k	0.605	1.85
10k	0.571	0.94
20k	0.538	0.47
50k	0.494	0.19
100k	0.464	0.10

Table 1: Diode characteristics measured in Part B.

$$\begin{array}{c|cccc} V_d \text{ (V)} & I_d \text{ (mA)} & V_{OC} \text{ (V)} \\ \hline 0.712 & 27.2 & 6.70 \end{array}$$

Table 2: Diode characteristics measured in Part C.